

#1/2
2/13/03

PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of

Saburo UEHARA

Art Unit: 2857

S. N. 09/805,811

Examiner: Mary C. Baran

Filed: March 13, 2001

For: SEMICONDUCTOR DEVICE TESTING
APPARATUS AND TEST METHOD THEREFOR

FAX RECEIVED

R E S P O N S E

FEB 21 2003

Commissioner for Patents
Washington, D.C. 20231

TECHNOLOGY CENTER 2800

Sir:

In response to the Office Action dated October 21, 2002, for which a 1 month extension of time is requested, to extend the period for response to February 21, 2003, please amend the above-identified application as follows:

In the specification:

Page 20, please amend the abstract by replacing it with the following. A markup is provided at the end of the response to indicate the changes made herein:

--In a semiconductor device testing apparatus and test method, after a pass value and fail value corresponding respectively to an upper limit and a lower limit of a test range have been set, measurement is not performed at these positions,